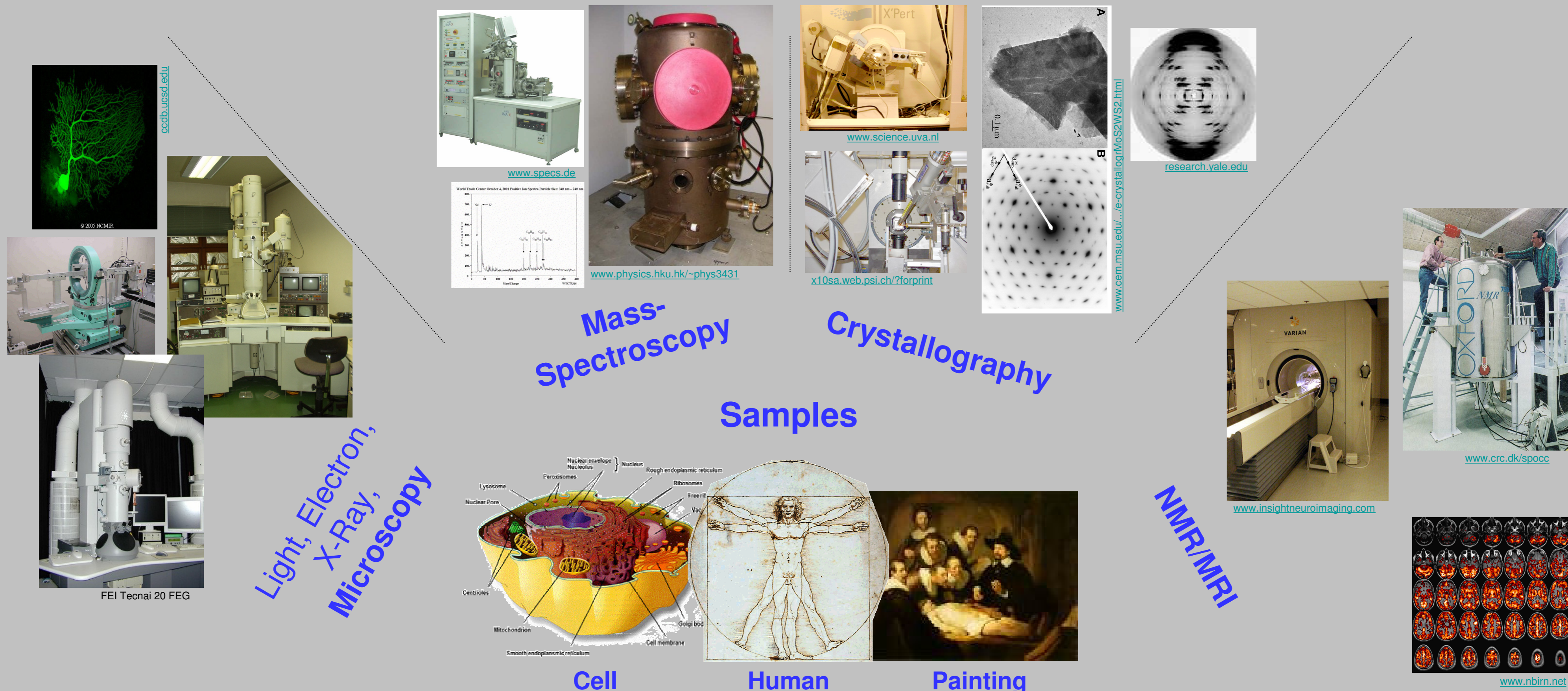




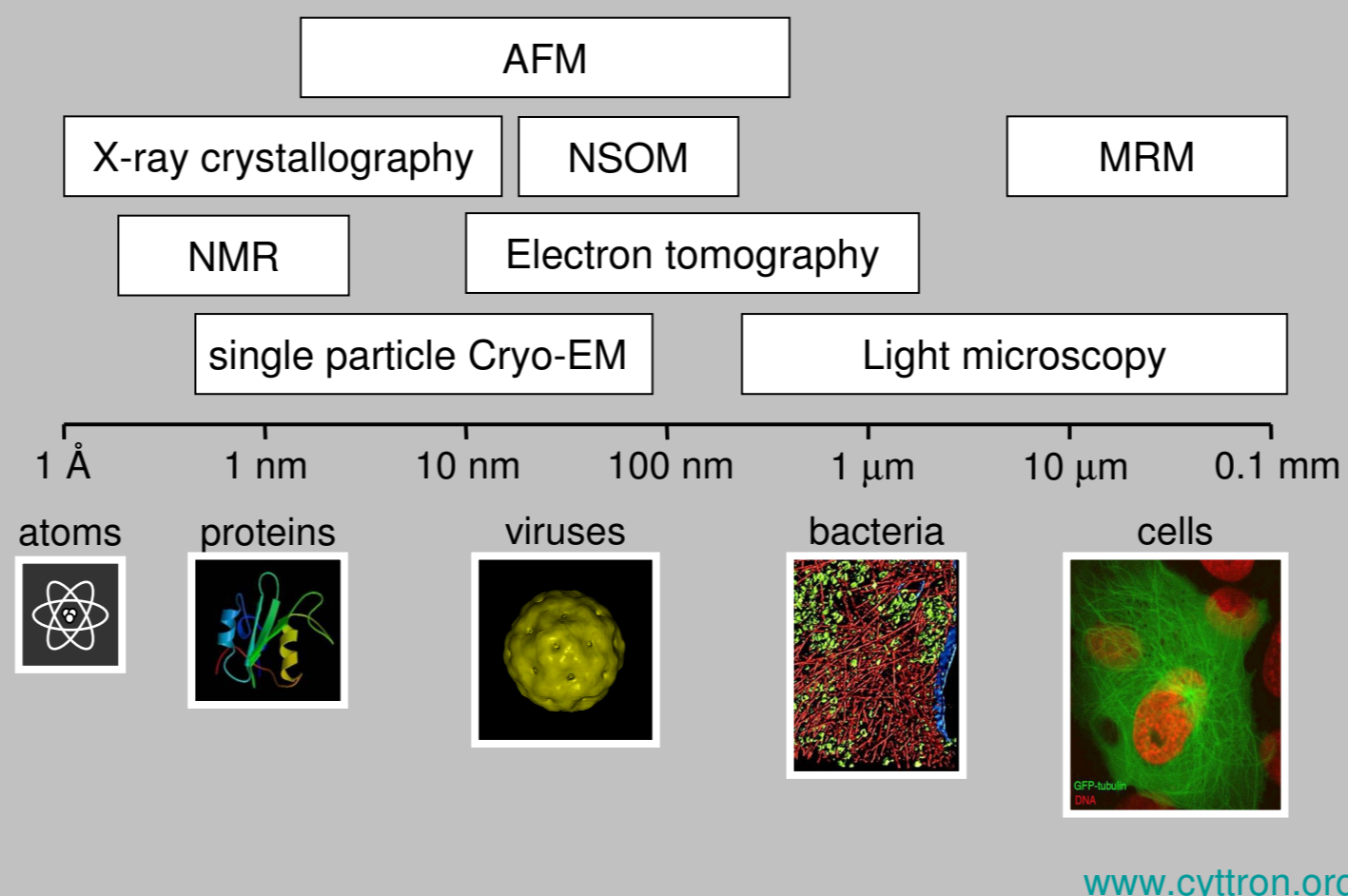
H. Hakan Yakali, Victor Guevara-Masis, L.O. Hertzberger (yakali, [vguevara](mailto:vguevara@science.uva.nl), bob@science.uva.nl) System and Network Engineering Group, University of Amsterdam



Equipment and Technology:

- Crystallography & Diffraction
- Atomic Force Microscopy (AFM)
- Confocal Laser Scanning Microscopy (CLSM)
- Near-field Scanning Optical Microscopy (NSOM)
- Scanning Tunneling Microscopy (STM)/ Scanned Probe Microscopy (SPM)
- X-ray Microscopy and Ion Beams
- Nano-technique & Nano-mechanics
- Nuclear Magnetic Resonance (NMR)
- Particle Beams
- Three-Dimensional (3-D) Imaging

<http://www.ou.edu/research/electron/www-vl/long.shtml>

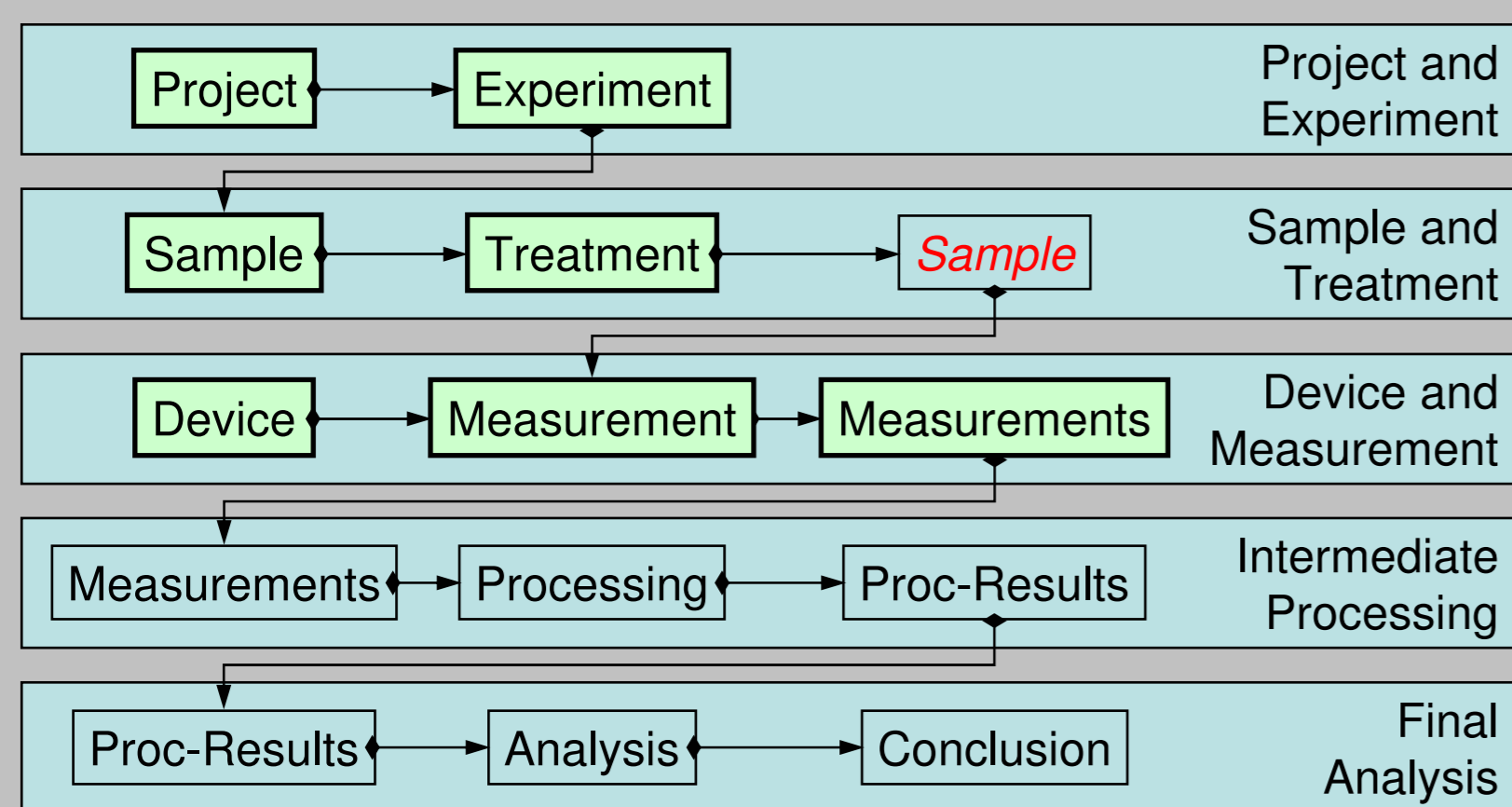


Despite the differences, all device measurement experiments have one of these:

- Hypothesis
- Experiment
- Sample
- Treatment Protocol
- Device
- Measurements
- Analysis

We capture these generic features in a high level Device Measurement Experiment workflow:

Device Measurement Experiment Workflow



Our Claim and Proposal

We claim this is sufficiently generic to represent just about any kind of Device Measurement Experimentation. If so, can we use this simple representation as basis to search other Device Measurement Experiments.

Goal is to stimulate:

- **Sharing** and collaboration among scientist and institutes
- thinking in multi-scale and in multi-dimensions hypothesis driven vs phenomenon discovery
- integration of Meta-MetaData (later)
- Realization of Virtual Microscopy (much later)

Questionnaire :

- Is this a sufficiently generalized representation of your device measurement experiments?
    - Yes
    - No
  - Would you or your institute collaborate on this system by providing very brief information about **Project**, **Experiment**, **Sample**, ... and a contact person for some of your experiments?
- If No, could you elaborate more? What would you change and how : (add/remove/rename) ?*

Summary

- Everyday many device measurement experiments are performed. Many results are sitting on the shelves nicely!!!
  - Different measurements devices and techniques provide complementary information.
  - These experiments have many common characteristics that can be captured in a high-level Device Measurement Experiment Workflow.
  - We propose a search engine using this representation:
 

**DevMea-Ex: Search Engine for Device Measurement Experiments**
  - Would you collaborate by sharing some of your data with some description
- Science is about sharing knowledge...

